Searcn Notes			
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/619,592	TAKAHASHI, AKIRA
Examiner	Art Unit
DuyVu n. Deo	1765

	SEARCHED		
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
438	700,706	11/7/2005	DVD
	714,717		
	723-725		

SEARCH (INCLUDING SEAR	NOTES CH STRATE(GY)
	DATE	EXMR
inventor search	11/7/200	5 DVD
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